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Re: Application number 10/087,825

Application title: Bonding of parts with dissimilar thermal expansion coefficients

Applicant: Kaspar Tobias Winther

Attached is a completed Form PTO-1449, copies of the references cited on this form and an overview of the prior art with explanations of how the prior art is different from the invention disclosed in this application.

Very respectfully,

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**Enclosures** 

## Prior Art Review

Application number 10/087,825 Applicant: Kaspar Tobias Winther

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Application title: Bonding of parts with dissimilar thermal expansion coefficients

application specific and as new products are developed new approaches follow. In particular many of the technology intensive products developed over the last years have called for creative ways around this problem. To simplify the review process the following table is provided showing the different types of general approaches that have been used. The present invention is most closely related to group F, although there are some fundamental differences, in particular in terms of how the intermediate zone is Thermal mismatch has been a major issue causing difficulties in the manufacture of a broad range of different products. Over the years a variety of different approaches have been developed to overcome these difficulties. Many of these approaches are very formed, the types of materials used and the types of bonding that can be applied. The cite numbers refer to patents based on a certain approach; some patents are utilizing a combination of multiple basic approaches.

Group	Group   General approach	Cite	Why this approach is inadequate	How the present invention
		No.		differ
A	Select materials to be bonded so	10, 16,	This approach puts unreasonable	Any material can be bonded.
	the thermal mismatch is minimal.	20, 22,	limitations on the selection of materials;	Both thermal mismatch and
		26, 28,	many devices will require materials that do	bonding problems are
		30, 32	not meet this criterion.	mitigated by the intermediate
				layer
В	Perform bonding at the lowest	03, 04,	The low temperature requirement means	A high lock in temperature and
	possible temperature to avoid	12, 23,	that many bonding methods cannot be	subsequent thermal cycles are
	residual forces or bond while the	27, 33	used. Some of the methods assume a	non-issues if the intermediate
	parts are maintained in the shape		single operating temperature and systems	layer matches their thermal
	and position they will have at the		that have to survive post-manufacturing	expansion coefficients of the
	usage temperature. Alternatively,		temperature cycles will perform in an	parts well. No compression
	selecting the optimal temperature		inferior manner. If compression is used it	required.
	and compression during bonding		may damage structures on the device.	
	can be used.			

מווטבי	General approach	Cite	Why this approach is inadequate	How the present invention
dinoito —		No.	and appropriate the second sec	differ
ပ	Minimize the overall bonding area	08, 11,	This approach at the same time gives a	The present invention allows
	between the two materials or	25	weak bond and opportunities for the parts	for full contact over an
	minimize the area of "undesired"		to shift slightly in position over time. If a	extended surface area.
<del></del>	(in terms of thermal expansion)		good thermal or electric contact is required	
	types of bonding agents.		this approach is highly counter productive.	
D	A compliant layer that can absorb	01, 06,	A compliant layer also allow for undesired	A completely rigid structure
	thermal mismatch placed between	07, 13,	motion. In particular for high precision	(e.g. silicon-glass-metal) is
	bonded members. Compliance	14, 19,	parts the tolerances cannot be met after a	constructed using the present
	can be achieved through elastic	21, 29,	large number of thermal cycles. For fairly	invention.
	deformation in the layer or	31, 51,	stiff materials that keep the parts better in	
	through grain boundary sliding.	52	place this layer can become quite thick.	
<	"Flexible" ridges or other			
-	structures can also form the layer.			
Ξ	Multi-layer bonding structure	02, (06)	Thermal mismatch will still remain	The present invention uses a
,	where each layer provides an		between the different discrete layers.	single layer and provides a
	acceptable step change in thermal		Often many layers are required adding	much smoother transition from
	expansion coefficient.		significantly to the fabrication cost. The	one part to the other.
		-	layers may in other respects have	
			undesirable properties.	
ഥ	Gradient in properties is achieved	02, 18,	The in-situ sintering or diffusion precludes	The layer used in the present
	through changing proportions of	53	using this method on most microsystems	invention can be externally
	powder metals or use of diffusion		technology products (MEMS / MST)	formed, and it is therefore
	bonding.		because the functional structures in the	much easier to achieve the
	)		devices will be destroyed by the	optimal compositional profile
			temperature required by the process. A	and it is possible to bond at a
			particulate precursor is undesirable	low temperature. Even if
			because particles can easily harm many	formed in-situ solid precursors
			MEMS devices. The use of metal is	of any kind can be used in the
			undesired for many devices.	present invention.

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explained above. There are no

can be constructed, as

between parts to be of use for most MEMS

05, 15, 17, 24, 30

This method allows for too much motion

Why this approach is inadequate

Cite No. limitations on the shape or

design.

A completely rigid structure

How the present invention

differ

The method disclosed offers a

much greater choice of

materials.

quantities of materials and more expensive

materials will have to be used.

parts is very restrictive. Often larger

The choice of materials and dimensions of

05,09

Select materials and designs that

H

can stand up to the strain.

/ MST devices. From a functional or design perspective the structures may not

be acceptable.

connecting surface has also been

used.

joined. A tapered edge by the

The design allows for relative motion between parts being

G

General approach

Group

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